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L1	15486	(three adj dimension$2 or 3D)and(ball adj grid adj array or BGA or terminals or lead$2)and inspect$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/18 12:13
L2	0	(three adj dimension$2 or 3D)and(ball adj grid adj array or BGA or terminals or lead$2)and inspect$3 and single near3(camera or ccd or detector$1 or sensor$1)with (two adj mirrors or two adj lenses or two adj optical adj elements)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/18 12:15

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```
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